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In re the Application of: YAMAGISHI, Yasuo, et al.

Group Art Unit: 2829

Serial No.: 10/621,445

Examiner: HOLLINGTON, Jermele M.

Filed: July 18, 2003

P.T.O. Confirmation No.: 1112

For. PROBE CARD AND TESTING METHOD OF SEMICONDUCTOR CHIP, CAPACITOR AND MANUFACTURING METHOD THEREOF

PETITION FOR EXTENSION OF TIME

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Date: May 10, 2005

Sir:

Applicants petition the Commissioner for Patents to extend the time for response to the Office Action dated January 10, 2005 for one month, from April 10, 2005 to May 10, 2005.

Attached please find a check in the amount of \$120.00 to cover the cost of the extension for a large entity. In the event that any additional fees are due in connection with this paper, please charge our Deposit Account No. 01-2340.

Respectfully submitted,

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